



## Future Normal in Semiconductor

2025-02-13(목), 09:00-10:45

좌장: 추후업데이트 예정

### G. Device & Process Modeling, Simulation and Reliability 분과

#### [TJ1-G] TCAD Simulation

<p>초청</p> <p>TJ1-G-1</p> <p>09:00-09:30</p>	<p><b>Impact of Random Discrete Dopants on 6F<sup>2</sup> DRAM Cell Transistors: A Simulation Study</b></p> <p>Jaehyun Lee School of Electrical and Electronics Engineering, Pusan National University</p>
<p>TJ1-G-2</p> <p>09:30-09:45</p>	<p><b>Effect of Metal-Capping Layer on Electrical Performances in a-IGZO TFTs: Experiment and TCAD Simulation</b></p> <p>Seongbin Lim<sup>1</sup>, Soohyun Lim<sup>1</sup>, Jaewook Yoo<sup>1</sup>, Hyeonjun Song<sup>1</sup>, Soyeon Kim<sup>1</sup>, Hongseung Lee<sup>1</sup>, Minah Park<sup>1</sup>, Seohyeon Park<sup>1</sup>, Sojin Jung<sup>1</sup>, Jin-Ha Hwang<sup>2</sup>, Kiyoun Lee<sup>2</sup>, Sangmoon Yoon<sup>3</sup>, and Hagyoul Bae <sup>1</sup>Jeonbuk National University, <sup>2</sup>Hongik University, and <sup>3</sup>Gachon University</p>
<p>TJ1-G-3</p> <p>09:45-10:00</p>	<p><b>Random Phase Distribution Effects of Ferroelectric Tunneling Field-Effect-Transistors (FeTFETs)</b></p> <p>Jiwon Park and Woo Young Choi Department Electrical and Computer Engineering and ISRC, Seoul National University</p>
<p>TJ1-G-4</p> <p>10:00-10:15</p>	<p><b>Assessment of Logic Circuit Characteristics with Contact Resistance in 2D Material-Based Complementary-FETs (CFETs)</b></p> <p>Hanggyo Jung<sup>1</sup> and Jongwook Jeon<sup>2</sup> Kyungpook National University</p>
<p>TJ1-G-5</p> <p>10:15-10:30</p>	<p><b>Comprehensive Analysis of Random Variability in Forksheet FETs Compared to Nanosheet FETs</b></p> <p>Minchan Kim, Seunghwan Lee, Junjong Lee, Sanguk Lee, Yonghwan Ahn, Gunryeol Cho, and Rock-Hyun Baek Department of Electrical Engineering, POSTECH</p>
<p>TJ1-G-6</p> <p>10:30-10:45</p>	<p><b>A Novel Simulation Method of Harmonic Distortion of RF Substrates Using Ramo-Shockley Theorem</b></p> <p>Nakwon Yu, Jongmin Kim, Youngchul Kim, and Hyunchul Nah TE Team, DB HiTek</p>